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## Understanding <u>Embedded - FPGAs (Field Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	42
Number of Logic Elements/Cells	336
Total RAM Bits	-
Number of I/O	68
Number of Gates	4000
Voltage - Supply	4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	84-LCC (J-Lead)
Supplier Device Package	84-PLCC (29.31x29.31)
Purchase URL	https://www.e-xfl.com/product-detail/intel/epf8452alc84-2

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

FLEX 8000 devices provide a large number of storage elements for applications such as digital signal processing (DSP), wide-data-path manipulation, and data transformation. These devices are an excellent choice for bus interfaces, TTL integration, coprocessor functions, and high-speed controllers. The high-pin-count packages can integrate multiple 32-bit buses into a single device. Table 3 shows FLEX 8000 performance and LE requirements for typical applications.

Table 3. FLEX 8000 Performance							
Application	LEs Used	Speed Grade Uni					
		A-2	A-3	A-4			
16-bit loadable counter	16	125	95	83	MHz		
16-bit up/down counter	16	125	95	83	MHz		
24-bit accumulator	24	87	67	58	MHz		
16-bit address decode	4	4.2	4.9	6.3	ns		
16-to-1 multiplexer	10	6.6	7.9	9.5	ns		

All FLEX 8000 device packages provide four dedicated inputs for synchronous control signals with large fan-outs. Each I/O pin has an associated register on the periphery of the device. As outputs, these registers provide fast clock-to-output times; as inputs, they offer quick setup times.

The logic and interconnections in the FLEX 8000 architecture are configured with CMOS SRAM elements. FLEX 8000 devices are configured at system power-up with data stored in an industry-standard parallel EPROM or an Altera serial configuration devices, or with data provided by a system controller. Altera offers the EPC1, EPC1213, EPC1064, and EPC1441 configuration devices, which configure FLEX 8000 devices via a serial data stream. Configuration data can also be stored in an industry-standard 32 K  $\times$  8 bit or larger configuration device, or downloaded from system RAM. After a FLEX 8000 device has been configured, it can be reconfigured in-circuit by resetting the device and loading new data. Because reconfiguration requires less than 100 ms, real-time changes can be made during system operation. For information on how to configure FLEX 8000 devices, go to the following documents:

- Configuration Devices for APEX & FLEX Devices Data Sheet
- BitBlaster Serial Download Cable Data Sheet
- ByteBlasterMV Parallel Port Download Cable Data Sheet
- Application Note 33 (Configuring FLEX 8000 Devices)
- Application Note 38 (Configuring Multiple FLEX 8000 Devices)

## **Logic Array Block**

A logic array block (LAB) consists of eight LEs, their associated carry and cascade chains, LAB control signals, and the LAB local interconnect. The LAB provides the coarse-grained structure of the FLEX 8000 architecture. This structure enables FLEX 8000 devices to provide efficient routing, high device utilization, and high performance. Figure 2 shows a block diagram of the FLEX 8000 LAB.



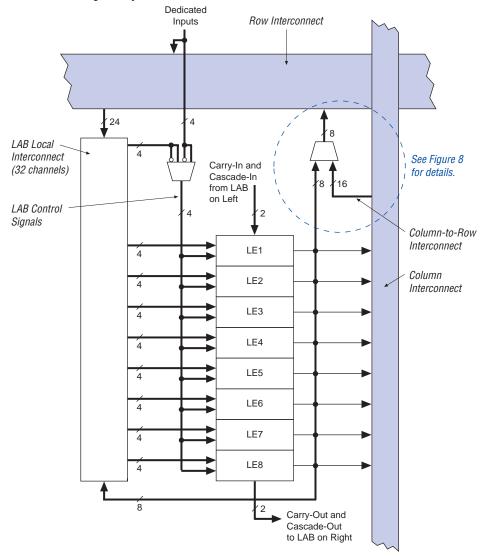
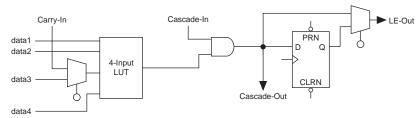
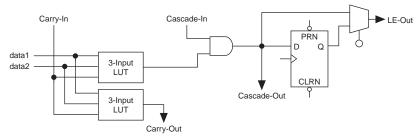


Figure 6. FLEX 8000 LE Operating Modes

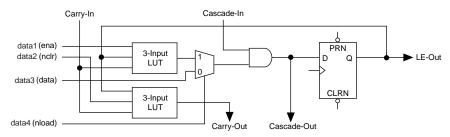
#### **Normal Mode**



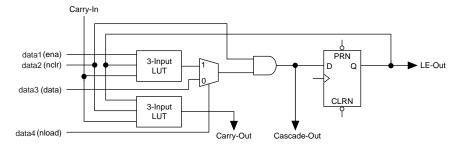
#### **Arithmetic Mode**



#### **Up/Down Counter Mode**



#### **Clearable Counter Mode**



#### Internal Tri-State Emulation

Internal tri-state emulation provides internal tri-stating without the limitations of a physical tri-state bus. In a physical tri-state bus, the tri-state buffers' output enable signals select the signal that drives the bus. However, if multiple output enable signals are active, contending signals can be driven onto the bus. Conversely, if no output enable signals are active, the bus will float. Internal tri-state emulation resolves contending tri-state buffers to a low value and floating buses to a high value, thereby eliminating these problems. The MAX+PLUS II software automatically implements tri-state bus functionality with a multiplexer.

#### Clear & Preset Logic Control

Logic for the programmable register's clear and preset functions is controlled by the DATA3, LABCTRL1, and LABCTRL2 inputs to the LE. The clear and preset control structure of the LE is used to asynchronously load signals into a register. The register can be set up so that LABCTRL1 implements an asynchronous load. The data to be loaded is driven to DATA3; when LABCTRL1 is asserted, DATA3 is loaded into the register.

During compilation, the MAX+PLUS II Compiler automatically selects the best control signal implementation. Because the clear and preset functions are active-low, the Compiler automatically assigns a logic high to an unused clear or preset.

The clear and preset logic is implemented in one of the following six asynchronous modes, which are chosen during design entry. LPM functions that use registers will automatically use the correct asynchronous mode. See Figure 7.

- Clear only
- Preset only
- Clear and preset
- Load with clear
- Load with preset
- Load without clear or preset

Each LE in an LAB can drive up to two separate column interconnect channels. Therefore, all 16 available column channels can be driven by the LAB. The column channels run vertically across the entire device, and share access to LABs in the same column but in different rows. The MAX+PLUS II Compiler chooses which LEs must be connected to a column channel. A row interconnect channel can be fed by the output of the LE or by two column channels. These three signals feed a multiplexer that connects to a specific row channel. Each LE is connected to one 3-to-1 multiplexer. In an LAB, the multiplexers provide all 16 column channels with access to 8 row channels.

Each column of LABs has a dedicated column interconnect that routes signals out of the LABs into the column. The column interconnect can then drive I/O pins or feed into the row interconnect to route the signals to other LABs in the device. A signal from the column interconnect, which can be either the output of an LE or an input from an I/O pin, must transfer to the row interconnect before it can enter an LAB. Table 4 summarizes the FastTrack Interconnect resources available in each FLEX 8000 device.

Table 4. FLEX 8000 FastTrack Interconnect Resources						
Device	Rows	Channels per Row	Columns	Channels per Column		
EPF8282A EPF8282AV	2	168	13	16		
EPF8452A	2	168	21	16		
EPF8636A	3	168	21	16		
EPF8820A	4	168	21	16		
EPF81188A	6	168	21	16		
EPF81500A	6	216	27	16		

Figure 9 shows the interconnection of four adjacent LABs, with row, column, and local interconnects, as well as the associated cascade and carry chains.

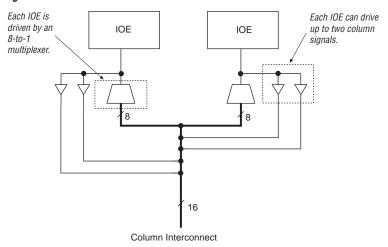


Figure 12. FLEX 8000 Column-to-IOE Connections

In addition to general-purpose I/O pins, FLEX 8000 devices have four dedicated input pins. These dedicated inputs provide low-skew, device-wide signal distribution, and are typically used for global clock, clear, and preset control signals. The signals from the dedicated inputs are available as control signals for all LABs and I/O elements in the device. The dedicated inputs can also be used as general-purpose data inputs because they can feed the local interconnect of each LAB in the device.

Signals enter the FLEX 8000 device either from the I/O pins that provide general-purpose input capability or from the four dedicated inputs. The IOEs are located at the ends of the row and column interconnect channels.

I/O pins can be used as input, output, or bidirectional pins. Each I/O pin has a register that can be used either as an input register for external data that requires fast setup times, or as an output register for data that requires fast clock-to-output performance. The MAX+PLUS II Compiler uses the programmable inversion option to invert signals automatically from the row and column interconnect when appropriate.

The clock, clear, and output enable controls for the IOEs are provided by a network of I/O control signals. These signals can be supplied by either the dedicated input pins or by internal logic. The IOE control-signal paths are designed to minimize the skew across the device. All control-signal sources are buffered onto high-speed drivers that drive the signals around the periphery of the device. This "peripheral bus" can be configured to provide up to four output enable signals (10 in EPF81500A devices), and up to two clock or clear signals. Figure 13 on page 22 shows how two output enable signals are shared with one clock and one clear signal.

The instruction register length for FLEX 8000 devices is three bits. Table 7 shows the boundary-scan register length for FLEX 8000 devices.

Table 7. FLEX 8000 Boundary-Scan Register Length				
Device Boundary-Scan Register Length				
EPF8282A, EPF8282AV	273			
EPF8636A	417			
EPF8820A 465				
EPF81500A	645			

FLEX 8000 devices that support JTAG include weak pull-ups on the JTAG pins. Figure 14 shows the timing requirements for the JTAG signals.

TDI

TCK

t<sub>JCP</sub>

t<sub>JCL</sub>

t<sub>JPSU</sub>

t<sub>JPSU</sub>

t<sub>JPNZ</sub>

TDO

Signal to Be Captured
Signal to Be Driven

Figure 14. EPF8282A, EPF8282AV, EPF8636A, EPF8820A & EPF81500A JTAG Waveforms

Table 8 shows the timing parameters and values for EPF8282A, EPF8282AV, EPF8636A, EPF8820A, and EPF81500A devices.

Table 1	Table 12. FLEX 8000 5.0-V Device Capacitance Note (8)					
Symbol	Parameter	Conditions Min Max Uni				
C <sub>IN</sub>	Input capacitance	V <sub>IN</sub> = 0 V, f = 1.0 MHz		10	pF	
C <sub>OUT</sub>	Output capacitance	V <sub>OUT</sub> = 0 V, f = 1.0 MHz		10	pF	

#### Notes to tables:

- (1) See the Operating Requirements for Altera Devices Data Sheet.
- (2) Minimum DC input is -0.5 V. During transitions, the inputs may undershoot to -2.0 V or overshoot to 7.0 V for input currents less than 100 mA and periods shorter than 20 ns.
- (3) The maximum V<sub>CC</sub> rise time is 100 ms.
- (4) Numbers in parentheses are for industrial-temperature-range devices.
- (5) Typical values are for  $T_A = 25^{\circ} \text{ C}$  and  $V_{CC} = 5.0 \text{ V}$ .
- (6) These values are specified in Table 10 on page 28.
- (7) The I<sub>OH</sub> parameter refers to high-level TTL or CMOS output current; the I<sub>OL</sub> parameter refers to low-level TTL or CMOS output current.
- (8) Capacitance is sample-tested only.

Tables 13 through 16 provide information on absolute maximum ratings, recommended operating conditions, operating conditions, and capacitance for 3.3-V FLEX 8000 devices.

Table 1	Table 13. FLEX 8000 3.3-V Device Absolute Maximum Ratings    Note (1)						
Symbol	Parameter	Conditions	Min	Max	Unit		
V <sub>CC</sub>	Supply voltage	With respect to ground (2)	-2.0	5.3	V		
V <sub>I</sub>	DC input voltage		-2.0	5.3	V		
I <sub>OUT</sub>	DC output current, per pin		-25	25	mA		
T <sub>STG</sub>	Storage temperature	No bias	-65	150	° C		
$T_{AMB}$	Ambient temperature	Under bias	-65	135	° C		
$T_{J}$	Junction temperature	Plastic packages, under bias		135	° C		

Table 1	Table 14. FLEX 8000 3.3-V Device Recommended Operating Conditions					
Symbol	Parameter	Conditions	Min	Max	Unit	
V <sub>CC</sub>	Supply voltage	(3)	3.0	3.6	V	
VI	Input voltage		-0.3	V <sub>CC</sub> + 0.3	V	
Vo	Output voltage		0	V <sub>CC</sub>	V	
T <sub>A</sub>	Operating temperature	For commercial use	0	70	° C	
t <sub>R</sub>	Input rise time			40	ns	
t <sub>F</sub>	Input fall time			40	ns	

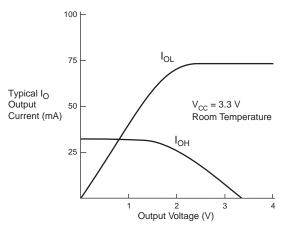


Figure 18. Output Drive Characteristics of EPF8282AV Devices

## **Timing Model**

The continuous, high-performance FastTrack Interconnect routing structure ensures predictable performance and accurate simulation and timing analysis. This predictable performance contrasts with that of FPGAs, which use a segmented connection scheme and hence have unpredictable performance. Timing simulation and delay prediction are available with the MAX+PLUS II Simulator and Timing Analyzer, or with industry-standard EDA tools. The Simulator offers both pre-synthesis functional simulation to evaluate logic design accuracy and post-synthesis timing simulation with 0.1-ns resolution. The Timing Analyzer provides point-to-point timing delay information, setup and hold time prediction, and device-wide performance analysis.

Tables 17 through 20 describe the FLEX 8000 timing parameters and their symbols.

Cumbal	Parameter
Symbol	Faiailietei
t <sub>IOD</sub>	IOE register data delay
t <sub>IOC</sub>	IOE register control signal delay
t <sub>IOE</sub>	Output enable delay
t <sub>IOCO</sub>	IOE register clock-to-output delay
t <sub>IOCOMB</sub>	IOE combinatorial delay
t <sub>IOSU</sub>	IOE register setup time before clock; IOE register recovery time after asynchronous clear
t <sub>IOH</sub>	IOE register hold time after clock
t <sub>IOCLR</sub>	IOE register clear delay
t <sub>IN</sub>	Input pad and buffer delay
t <sub>OD1</sub>	Output buffer and pad delay, slow slew rate = off, $V_{CCIO} = 5.0 \text{ V C1} = 35 \text{ pF}$ (2)
t <sub>OD2</sub>	Output buffer and pad delay, slow slew rate = off, $V_{CCIO} = 3.3 \text{ V C1} = 35 \text{ pF } (2)$
t <sub>OD3</sub>	Output buffer and pad delay, slow slew rate = on, C1 = 35 pF (3)
$t_{XZ}$	Output buffer disable delay, C1 = 5 pF
$t_{ZX1}$	Output buffer enable delay, slow slew rate = off, V <sub>CCIO</sub> = 5.0 V, C1 = 35 pF (2)
$t_{ZX2}$	Output buffer enable delay, slow slew rate = off, V <sub>CCIO</sub> = 3.3 V, C1 = 35 pF (2)
$t_{ZX3}$	Output buffer enable delay, slow slew rate = on, C1 = 35 pF (3)

Table 18. F	Table 18. FLEX 8000 LE Timing Parameters   Note (1)			
Symbol	Parameter			
$t_{LUT}$	LUT delay for data-in			
t <sub>CLUT</sub>	LUT delay for carry-in			
t <sub>RLUT</sub>	LUT delay for LE register feedback			
t <sub>GATE</sub>	Cascade gate delay			
t <sub>CASC</sub>	Cascade chain routing delay			
t <sub>CICO</sub>	Carry-in to carry-out delay			
t <sub>CGEN</sub>	Data-in to carry-out delay			
t <sub>CGENR</sub>	LE register feedback to carry-out delay			
$t_{C}$	LE register control signal delay			
t <sub>CH</sub>	LE register clock high time			
t <sub>CL</sub>	LE register clock low time			
$t_{CO}$	LE register clock-to-output delay			
t <sub>COMB</sub>	Combinatorial delay			
t <sub>SU</sub>	LE register setup time before clock; LE register recovery time after asynchronous preset, clear, or load			
$t_H$	LE register hold time after clock			
t <sub>PRE</sub>	LE register preset delay			
t <sub>CLR</sub>	LE register clear delay			

Table 19. FLEX 8000 Interconnect Timing Parameters Note (1)				
Symbol	Parameter			
t <sub>LABCASC</sub>	Cascade delay between LEs in different LABs			
t <sub>LABCARRY</sub>	Carry delay between LEs in different LABs			
t <sub>LOCAL</sub>	LAB local interconnect delay			
t <sub>ROW</sub>	Row interconnect routing delay (4)			
$t_{COL}$	Column interconnect routing delay			
t <sub>DIN_C</sub>	Dedicated input to LE control delay			
t <sub>DIN_D</sub>	Dedicated input to LE data delay (4)			
t <sub>DIN_IO</sub>	Dedicated input to IOE control delay			

Table 20. FLEX 8000 External Reference Timing Characteristics    Note (5)				
Symbol	Parameter			
t <sub>DRR</sub>	egister-to-register delay via 4 LEs, 3 row interconnects, and 4 local interconnects (6)			
t <sub>ODH</sub>	Output data hold time after clock (7)			

#### Notes to tables:

- (1) Internal timing parameters cannot be measured explicitly. They are worst-case delays based on testable and external parameters specified by Altera. Internal timing parameters should be used for estimating device performance. Post-compilation timing simulation or timing analysis is required to determine actual worst-case performance.
- (2) These values are specified in Table 10 on page 28 or Table 14 on page 29.
- (3) For the  $t_{OD3}$  and  $t_{ZX3}$  parameters,  $V_{CCIO} = 3.3 \text{ V or } 5.0 \text{ V}$ .
- (4) The  $t_{ROW}$  and  $t_{DIN\_D}$  delays are worst-case values for typical applications. Post-compilation timing simulation or timing analysis is required to determine actual worst-case performance.
- (5) External reference timing characteristics are factory-tested, worst-case values specified by Altera. A representative subset of signal paths is tested to approximate typical device applications.
- (6) For more information on test conditions, see *Application Note 76* (*Understanding FLEX 8000 Timing*).
- (7) This parameter is a guideline that is sample-tested only and is based on extensive device characterization. This parameter applies to global and non-global clocking, and for LE and I/O element registers.

The FLEX 8000 timing model shows the delays for various paths and functions in the circuit. See Figure 19. This model contains three distinct parts: the LE; the IOE; and the interconnect, including the row and column FastTrack Interconnect, LAB local interconnect, and carry and cascade interconnect paths. Each parameter shown in Figure 19 is expressed as a worst-case value in Tables 22 through 49. Hand-calculations that use the FLEX 8000 timing model and these timing parameters can be used to estimate FLEX 8000 device performance. Timing simulation or timing analysis after compilation is required to determine the final worst-case performance. Table 21 summarizes the interconnect paths shown in Figure 19.



For more information on timing parameters, go to *Application Note 76* (*Understanding FLEX 8000 Timing*).

Symbol			Speed	l Grade			Unit
	A	-2	A-3		A-4		
	Min	Max	Min	Max	Min	Max	
$t_{LUT}$		2.0		2.5		3.2	ns
t <sub>CLUT</sub>		0.0		0.0		0.0	ns
t <sub>RLUT</sub>		0.9		1.1		1.5	ns
t <sub>GATE</sub>		0.0		0.0		0.0	ns
t <sub>CASC</sub>		0.6		0.7		0.9	ns
t <sub>CICO</sub>		0.4		0.5		0.6	ns
t <sub>CGEN</sub>		0.4		0.5		0.7	ns
t <sub>CGENR</sub>		0.9		1.1		1.5	ns
$t_C$		1.6		2.0		2.5	ns
t <sub>CH</sub>	4.0		4.0		4.0		ns
$t_{CL}$	4.0		4.0		4.0		ns
$t_{CO}$		0.4		0.5		0.6	ns
t <sub>COMB</sub>		0.4		0.5		0.6	ns
t <sub>SU</sub>	0.8		1.1		1.2		ns
t <sub>H</sub>	0.9		1.1		1.5		ns
t <sub>PRE</sub>		0.6		0.7		0.8	ns
t <sub>CLR</sub>		0.6		0.7		0.8	ns

Table 25. EPF8282A External Timing Parameters											
Symbol	Speed Grade										
	A	A-2 A-3				A-4					
	Min	Max	Min	Max	Min	Max					
t <sub>DRR</sub>		15.8		19.8		24.8	ns				
t <sub>ODH</sub>	1.0		1.0		1.0		ns				

Symbol			Speed	Grade			Unit
	A-2		A-3		А	-4	
	Min	Max	Min	Max	Min	Max	
$t_{LUT}$		2.0		2.3		3.0	ns
t <sub>CLUT</sub>		0.0		0.2		0.1	ns
t <sub>RLUT</sub>		0.9		1.6		1.6	ns
$t_{GATE}$		0.0		0.0		0.0	ns
t <sub>CASC</sub>		0.6		0.7		0.9	ns
t <sub>CICO</sub>		0.4		0.5		0.6	ns
t <sub>CGEN</sub>		0.4		0.9		0.8	ns
t <sub>CGENR</sub>		0.9		1.4		1.5	ns
$t_{\rm C}$		1.6		1.8		2.4	ns
t <sub>CH</sub>	4.0		4.0		4.0		ns
$t_{CL}$	4.0		4.0		4.0		ns
$t_{\rm CO}$		0.4		0.5		0.6	ns
t <sub>COMB</sub>		0.4		0.5		0.6	ns
t <sub>SU</sub>	0.8		1.0		1.1		ns
t <sub>H</sub>	0.9		1.1		1.4		ns
t <sub>PRE</sub>		0.6		0.7		0.8	ns
t <sub>CLR</sub>		0.6		0.7		0.8	ns

Table 33. EPF8452A External Timing Parameters										
Symbol	Speed Grade									
	A-2		A-3		A-4					
	Min	Max	Min	Max	Min	Max				
t <sub>DRR</sub>		16.0		20.0		25.0	ns			
t <sub>ODH</sub>	1.0		1.0		1.0		ns			

Table 36. EPF8636A LE Timing Parameters										
Symbol			Speed G	irade			Unit			
	A-2		A-3		A-4		1			
	Min	Max	Min	Max	Min	Max				
$t_{LUT}$		2.0		2.3		3.0	ns			
$t_{CLUT}$		0.0		0.2		0.1	ns			
t <sub>RLUT</sub>		0.9		1.6		1.6	ns			
t <sub>GATE</sub>		0.0		0.0		0.0	ns			
t <sub>CASC</sub>		0.6		0.7		0.9	ns			
t <sub>CICO</sub>		0.4		0.5		0.6	ns			
t <sub>CGEN</sub>		0.4		0.9		0.8	ns			
t <sub>CGENR</sub>		0.9		1.4		1.5	ns			
$t_{C}$		1.6		1.8		2.4	ns			
t <sub>CH</sub>	4.0		4.0		4.0		ns			
t <sub>CL</sub>	4.0		4.0		4.0		ns			
$t_{CO}$		0.4		0.5		0.6	ns			
t <sub>COMB</sub>		0.4		0.5		0.6	ns			
t <sub>SU</sub>	0.8		1.0		1.1		ns			
t <sub>H</sub>	0.9		1.1		1.4		ns			
t <sub>PRE</sub>		0.6		0.7		0.8	ns			
t <sub>CLR</sub>		0.6		0.7		0.8	ns			

Table 37. EPF8636A External Timing Parameters										
Symbol	Speed Grade									
	A	-2	А	A-3		A-4				
	Min	Max	Min	Max	Min	Max				
t <sub>DRR</sub>		16.0		20.0		25.0	ns			
t <sub>ODH</sub>	1.0		1.0		1.0		ns			

Table 40. EPF882	POA LE Timing	Parameters					
Symbol			Speed	Grade			Unit
	A-2		A-3		A	1-4	
	Min	Max	Min	Max	Min	Max	
$t_{LUT}$		2.0		2.5		3.2	ns
t <sub>CLUT</sub>		0.0		0.0		0.0	ns
t <sub>RLUT</sub>		0.9		1.1		1.5	ns
$t_{GATE}$		0.0		0.0		0.0	ns
t <sub>CASC</sub>		0.6		0.7		0.9	ns
t <sub>CICO</sub>		0.4		0.5		0.6	ns
t <sub>CGEN</sub>		0.4		0.5		0.7	ns
t <sub>CGENR</sub>		0.9		1.1		1.5	ns
$t_C$		1.6		2.0		2.5	ns
t <sub>CH</sub>	4.0		4.0		4.0		ns
t <sub>CL</sub>	4.0		4.0		4.0		ns
$t_{CO}$		0.4		0.5		0.6	ns
t <sub>COMB</sub>		0.4		0.5		0.6	ns
t <sub>SU</sub>	0.8		1.1		1.2		ns
t <sub>H</sub>	0.9		1.1		1.5		ns
t <sub>PRE</sub>		0.6		0.7		0.8	ns
t <sub>CLR</sub>		0.6		0.7		0.8	ns

Table 41. EPF8820A External Timing Parameters										
Symbol	Speed Grade									
	A-2 A-3 A-4					-4				
	Min	Max	Min	Max	Min	Max				
t <sub>DRR</sub>		16.0		20.0		25.0	ns			
t <sub>ODH</sub>	1.0		1.0		1.0		ns			

Table 48. EPF81500A LE Timing Parameters										
Symbol			Speed	Grade			Unit			
	A-2		А	-3	А	-4				
	Min	Max	Min	Max	Min	Max				
$t_{LUT}$		2.0		2.5		3.2	ns			
$t_{CLUT}$		0.0		0.0		0.0	ns			
t <sub>RLUT</sub>		0.9		1.1		1.5	ns			
t <sub>GATE</sub>		0.0		0.0		0.0	ns			
t <sub>CASC</sub>		0.6		0.7		0.9	ns			
$t_{CICO}$		0.4		0.5		0.6	ns			
t <sub>CGEN</sub>		0.4		0.5		0.7	ns			
t <sub>CGENR</sub>		0.9		1.1		1.5	ns			
$t_C$		1.6		2.0		2.5	ns			
t <sub>CH</sub>	4.0		4.0		4.0		ns			
$t_{CL}$	4.0		4.0		4.0		ns			
$t_{CO}$		0.4		0.5		0.6	ns			
t <sub>COMB</sub>		0.4		0.5		0.6	ns			
t <sub>SU</sub>	0.8		1.1		1.2		ns			
$t_H$	0.9		1.1		1.5		ns			
t <sub>PRE</sub>		0.6		0.7		0.8	ns			
t <sub>CLR</sub>		0.6		0.7		0.8	ns			

Table 49. EPF81500A External Timing Parameters										
Symbol		Speed Grade								
	A-2		A-3		A-4		1			
	Min	Max	Min	Max	Min	Max	1			
t <sub>DRR</sub>		16.1		20.1		25.1	ns			
t <sub>ODH</sub>	1.0		1.0		1.0		ns			

# Power Consumption

The supply power (P) for FLEX 8000 devices can be calculated with the following equation:

$$P = P_{INT} + P_{IO} = [(I_{CCSTANDBY} + I_{CCACTIVE}) \times V_{CC}] + P_{IO}$$

Typical  $I_{CCSTANDBY}$  values are shown as  $I_{CC0}$  in Table 11 on page 28 and Table 15 on page 30. The  $P_{IO}$  value, which depends on the device output load characteristics and switching frequency, can be calculated using the guidelines given in *Application Note 74 (Evaluating Power for Altera Devices)*. The  $I_{CCACTIVE}$  value depends on the switching frequency and the application logic. This value can be calculated based on the amount of current that each LE typically consumes.

The following equation shows the general formula for calculating  $I_{\text{CCACTIVE}}$ :

$$I_{CCACTIVE} \, = \, K \times f_{MAX} \times N \times tog_{LC} \times \frac{\mu A}{MHz \times LE}$$

The parameters in this equation are shown below:

f<sub>MAX</sub> = Maximum operating frequency in MHz
 N = Total number of logic cells used in the device

tog<sub>LC</sub> = Average percentage of logic cells toggling at each clock

K = Constant, shown in Table 50

Table 50. Values for Constant K						
Device	K					
5.0-V FLEX 8000 devices	75					
3.3-V FLEX 8000 devices	60					

This calculation provides an  $I_{CC}$  estimate based on typical conditions with no output load. The actual  $I_{CC}$  value should be verified during operation because this measurement is sensitive to the actual pattern in the device and the environmental operating conditions.

Figure 20 shows the relationship between  $I_{CC}$  and operating frequency for several LE utilization values.

Pin Name	84-Pin	84-Pin	100-Pin	100-Pin	144-Pin	160-Pin	160-Pin
	PLCC EPF8282A	PLCC EPF8452A EPF8636A	TQFP EPF8282A EPF8282AV	TQFP EPF8452A	TQFP EPF8820A	PGA EPF8452A	PQFP EPF8820A (1)
ADD0	78	76	78	77	106	N3	6
DATA7	3	2	90	89	131	P8	140
DATA6	4	4	91	91	132	P10	139
DATA5	6	6	92	95	133	R12	138
DATA4	7	7	95	96	134	R13	136
DATA3	8	8	97	97	135	P13	135
DATA2	9	9	99	98	137	R14	133
DATA1	13	13	4	4	138	N15	132
DATA0	14	14	5	5	140	K13	129
SDOUT (3)	79	78	79	79	23	P4	97
TDI (4)	55	45 (5)	54	_	96	_	17
TDO (4)	27	27 (5)	18	_	18	_	102
TCK (4), (6)	72	44 (5)	72	_	88	_	27
TMS (4)	20	43 (5)	11	_	86	_	29
TRST (7)	52	52 (8)	50	_	71	_	45
Dedicated	12, 31, 54,	12, 31, 54,	3, 23, 53, 73	3, 24, 53,	9, 26, 82,	C3, D14,	14, 33, 94,
Inputs (10)	73	73		74	99	N2, R15	113
VCCINT	17, 38, 59, 80	17, 38, 59, 80	6, 20, 37, 56, 70, 87	9, 32, 49, 59, 82	8, 28, 70, 90, 111	B2, C4, D3, D8, D12, G3, G12, H4, H13, J3, J12, M4, M7, M9, M13, N12	3, 24, 46, 92, 114, 160
VCCIO	-	_	_	_	16, 40, 60, 69, 91, 112, 122, 141	_	23, 47, 57, 69, 79, 104, 127, 137, 149, 159

Pin Name	160-Pin PQFP EPF8452A	160-Pin PQFP EPF8636A	192-Pin PGA EPF8636A EPF8820A	208-Pin PQFP EPF8636A (1)	208-Pin PQFP EPF8820A (1)	208-Pin PQFP EPF81188A (1)
DATA4	154	127	E17	165	172	170
DATA3	157	124	G15	162	171	168
DATA2	159	122	F15	160	167	166
DATA1	11	115	E16	149	165	163
DATA0	12	113	C16	147	162	161
SDOUT (3)	128	152	C7 (11)	198	124	119
TDI (4)	_	55	R11	72	20	-
TDO (4)	_	95	B9	120	129	-
TCK (4), (6)	_	57	U8	74	30	-
TMS (4)	_	59	U7	76	32	_
TRST (7)	_	40	R3	54	54	_
Dedicated Inputs (10)	5, 36, 85, 116	6, 35, 87, 116	A5, U5, U13, A13	7, 45, 112, 150	17, 36, 121, 140	13, 41, 116, 146
VCCINT (5.0 V)	21, 41, 53, 67, 80, 81, 100, 121, 133, 147, 160	4, 5, 26, 85, 106	C8, C9, C10, R8, R9, R10, R14	5, 6, 33, 110, 137	5, 6, 27, 48, 119, 141	4, 20, 35, 48, 50, 102, 114, 131, 147
VCCIO (5.0 V or 3.3 V)	_	25, 41, 60, 70, 80, 107, 121, 140, 149, 160	D3, D4, D9, D14, D15, G4, G14, L4, L14, P4, P9, P14	32, 55, 78, 91, 102, 138, 159, 182, 193, 206	26, 55, 69, 87, 102, 131, 159, 173, 191, 206	3, 19, 34, 49, 69, 87, 106, 123, 140, 156, 174, 192
GND	13, 14, 28, 46, 60, 75, 93, 107, 108, 126, 140, 155	15, 16, 36, 37, 45, 51, 75, 84, 86, 96, 97, 117, 126, 131, 154	C4, D7, D8, D10, D11, H4, H14, K4, K14, P7, P8, P10, P11	19, 20, 46, 47, 60, 67, 96, 109, 111, 124, 125, 151, 164, 171, 200	15, 16, 37, 38, 60, 78, 96, 109, 110, 120, 130, 142, 152, 164, 182, 200	11, 12, 27, 28, 42, 43, 60, 78, 96, 105, 115, 122, 132, 139, 148, 155, 159, 165, 183, 201
No Connect (N.C.)	2, 3, 38, 39, 70, 82, 83, 118, 119, 148	2, 39, 82, 119	C6, C12, C13, C14, E3, E15, F3, J3, J4, J14, J15, N3, N15, P3, P15, R4 (12)	1, 2, 3, 16, 17, 18, 25, 26, 27, 34, 35, 36, 50, 51, 52, 53, 104, 105, 106, 107, 121, 122, 123, 130, 131, 132, 139, 140, 141, 154, 155, 156, 157, 208	1, 2, 3, 50, 51, 52, 53, 104, 105, 106, 107, 154, 155, 156, 157, 208	1, 2, 51, 52, 53, 54, 103, 104, 157, 158, 207, 208
Total User I/O Pins (9)	116	114	132, 148 (13)	132	148	144

Pin Name	225-Pin BGA	232-Pin PGA	240-Pin PQFP	240-Pin PQFP	280-Pin PGA	304-Pin RQFP
	EPF8820A	EPF81188A	EPF81188A	EPF81500A	EPF81500A	EPF81500A
nSP <i>(2)</i>	A15	C14	237	237	W1	304
MSEL0 (2)	B14	G15	21	19	N1	26
MSEL1 (2)	R15	L15	40	38	H3	51
nSTATUS (2)	P2	L3	141	142	G19	178
nCONFIG (2)	R1	R4	117	120	B18	152
DCLK (2)	B2	C4	184	183	U18	230
CONF_DONE (2)	A1	G3	160	161	M16	204
nWS	L4	P1	133	134	F18	167
nRS	K5	N1	137	138	G18	171
RDCLK	F1	G2	158	159	M17	202
nCS	D1	E2	166	167	N16	212
CS	C1	E3	169	170	N18	215
RDYnBUSY	J3	K2	146	147	J17	183
CLKUSR	G2	H2	155	156	K19	199
ADD17	M14	R15	58	56	E3	73
ADD16	L12	T17	56	54	E2	71
ADD15	M15	P15	54	52	F4	69
ADD14	L13	M14	47	45	G1	60
ADD13	L14	M15	45	43	H2	58
ADD12	K13	M16	43	41	H1	56
ADD11	K15	K15	36	34	J3	47
ADD10	J13	K17	34	32	K3	45
ADD9	J15	J14	32	30	K4	43
ADD8	G14	J15	29	27	L1	34
ADD7	G13	H17	27	25	L2	32
ADD6	G11	H15	25	23	M1	30
ADD5	F14	F16	18	16	N2	20
ADD4	E13	F15	16	14	N3	18
ADD3	D15	F14	14	12	N4	16
ADD2	D14	D15	7	5	U1	8
ADD1	E12	B17	5	3	U2	6
ADD0	C15	C15	3	1	V1	4
DATA7	A7	A7	205	199	W13	254
DATA6	D7	D8	203	197	W14	252
DATA5	A6	B7	200	196	W15	250